Search Notes	Application/Control No.	Applicant(s)/Patent under Reexamination TANAKA ET AL.	
	10/028,778		
	Examiner	Art Unit	
1 100 101 11011 100117 100117 100117 100117 100117 10001 10117 1001	Fazli Erdem	2826	

SEARCHED				•	SEARCH NO	IOTES CH STRATEGY)		
Class	Subclass	Date	Examiner			DATE	EXMR	
-					Updated SON	1-oluts	R.	
							<u> </u>	
		·						
		*			·			
						;		
						1	l	
			-					
···						<u></u>		
INT	ERFERENC	CE SEARCH	FD				•	
Class	Subclass	Date	Examiner					
					L	_		
					ı			
			! I			1		